

Biometric Consortium 2004 Conference

Fernando L. Podio

Co-Chair

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Biography: Fernando L. Podio is a member of the Computer Security Division of the Information Technology Laboratory at the National Institute of Standards and Technology (NIST). He has worked at NIST since 1983. He has been involved in different aspects of IT development, measurements, and standards for over twenty-five years. For the past five years he has been involved in biometrics research and standardization. He is currently responsible for the NIST Program on Accelerating the Development of Critical Biometric Standards & Associated Conformity Assessment Activities. Before his work in biometrics began, he conducted research and testing of intelligent data storage devices, sequential data storage media and optical digital data disks. He chairs the InterNational Committee for Information Technology Standards (INCITS) Technical Committee M1, Biometrics, and is the Chairman of ISO/IEC Joint Technical Committee 1 (JTC 1) Subcommittee 37 (SC 37) - Biometrics. He also co-chairs the Biometric Consortium (BC) which is an organization of over one thousand members from Government, industry, academia. Thirty-eight countries are represented within its membership. He has shared a 2003 group US Department of Commerce Gold Medal Award for Distinguished Achievement in the Federal Service for “development of standards, testing methodology, and metrics for biometric technologies to be used for securing the Nation’s borders”. He has also received the InterNational Committee for IT Standards Gene Milligan Award in recognition of his leadership work in biometrics standards. His involvement in biometrics also led to two other awards, NIST’s 2000 William P. Slichter Award for “Outstanding Achievement in building or strengthening ties between NIST and industry” and a Federal Laboratory Consortium for Technology Transfer award for technology transfer of biometric specifications to industry.